

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 10/710,308 | Applicant(s)/Patent Under Reexamination BONALLE ET AL. | |
| | Examiner Daniel I. Walsh | Art Unit 2876 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------------|----------------|
| * | A | US-5,721,781 | 02-1998 | Deo et al. | 705/67 |
| * | B | US-6,834,795 | 12-2004 | Rasmussen et al. | 235/380 |
| * | C | US-2005/0065872 | 03-2005 | Moebs et al. | 705/038 |
| * | D | US-2005/0098621 | 05-2005 | de Sylva, Robert Francis | 235/379 |
| * | E | US-2005/0122209 | 06-2005 | Black, Gerald R. | 340/005.52 |
| * | F | US-2005/0232471 | 10-2005 | Baer, Richard | 382/115 |
| * | G | US-6,095,413 | 08-2000 | Tetro et al. | 235/380 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.